

The 37th RD50 Workshop (Zagreb -- online Workshop)

Wednesday, 18 November 2020

Detector Characterization and Simulation (13:30 - 16:40)

-Conveners: Joern Schwandt; Gianluigi Casse

time	[id] title	presenter
13:30	[26] Analysis of I-V characteristics as a method in the study of radiation degradation of Si detectors	Dr EREMIN, Vladimir
13:50	[34] Radiation effects in the CMS phase 1 pixel detector	BRZHECHKO, Danyyl
14:10	[51] Measurements of Sensor Radiation Damage in the ATLAS Inner Detector using Leakage Currents	GRUMMER, Aidan SEIDEL, Sally
14:30	[29] Determination of proton hardness factors with commercial PiN diodes	KNIGHTS, Patrick Ryan
14:50	[13] Gamma, neutron, proton irradiated p-type silicon MOS capacitors with aluminium oxide.	GOLOVLEVA, Maria
15:10	Coffee Break	
15:30	[9] Irradiation of gate-controlled diodes and MOS capacitors with ^{60}Co -gamma photons	ASENOV, Patrick
15:50	[36] Update on radiation damage investigation of epitaxial p-type silicon using Schottky and pn-junction diodes	KLEIN, Christoph Thomas
16:10	[39] Discussion: Detector Characterization and Simulation	CASSE, Gianluigi SCHWANDT, Joern